



OptiMOS[™]3 Power MOS Transistor Chip

Туре	V _{(BR)DSS}	R _{DS(on)}	Die size	Thickness
IPC302N25N3	250 V	$20 \text{ m}\Omega^{1)}$	6.7 * 4.5 mm ²	250 μm

DESCRIPTION

- N-channel enhancement mode
- For additional characteristic and max rating refer to the datasheet of IPP200N25N3 G
- AQL 0.65 for visual inspection according to failure catalogue
- Electrostatic Discharge Sensitive Device according to MIL-STD 883C
- Die bond: soldered or glued
- Backside metallization: NiV system
- Frontside metallization: AlCu system
- Passivation: nitride (only on edge structure)
- Package: sawn on foil

Electrical Characteristics on Wafer Level

at $T_i = 25 \text{ °C}$, unless otherwise specified.

Parameter	Symbol	Value			Unit	Conditions
		min.	typ.	max.		
Drain-source breakdown voltage	V _{(BR)DSS}	250	-	-	V	$V_{GS} = 0V$
						$I_D = 1 \text{ mA}$
Gate threshold voltage	V _{GS(th)}	2	3	4	V	$V_{DS} = V_{GS}$
						I _D = 270 μA
Zero gate voltage drain current	IDSS	-	0.1	1	μA	$V_{GS} = 0V$
						V _{DS} = 200 V
Gate-source leakage current	I _{GSS}	-	1	100	nA	$V_{GS} = 20 V$
						$V_{DS} = 0 V$
Drain-source on-resistance	$R_{\rm DS(on)}$	-	16 ³⁾	100 ²⁾	mΩ	V _{GS} = 10 V
						I _D = 2 A
Reverse diode forward on-voltage	$V_{\rm SD}$	-	0.7	1.2	V	V _{GS} =0 V
						I _F = 1 A
Avalanche energy, single pulse	Eas	-	40 ⁴⁾	-	mJ	$I_D = 30 \text{ A}, R_{GS} = 25 \Omega$

¹⁾ packaged in a PG-TO220-3 (see ref. product)

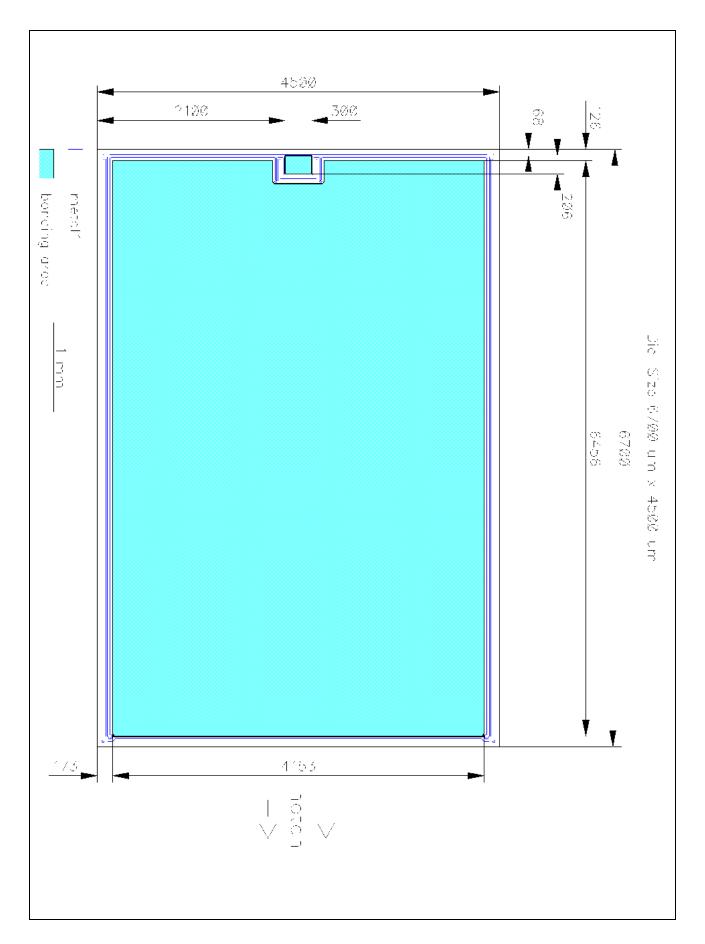
²⁾ limited by wafer test-equipment

 $^{3)}$ typical bare die $R_{\text{DS(on)}}; V_{\text{GS}}{=}10V$

⁴⁾ Wafer tested. For general avalanche capability refer to the datasheet of IPP200N25N3 G



IPC302N25N3







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